

## **TEST / CALIBRATION REPORT**

# **EMC / EMI Test Report**for MECO Digital Multimeter

Testing as per BS EN 61326 (Edition 1998)



# **ELECTRONICS REGIONAL TEST LABORATORY (WEST)**

MINISTRY OF COMMUNICATIONS & INFORMATION TECHNOLOGY, (STQC Dte.)

## Government of India

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## **MEMORANDUM**

The Test/Calibration Report issued by **ERTL** (W) is a record of the measurements conducted on the products submitted to it for testing / calibration and the results thereof. Unless otherwise specified in the report, the results are applicable only to those products which have been tested / calibrated and do not apply to other products even though declared to be identical.

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## **LIABILITY CLAUSE**

- ERTL (W) shall not be liable for any change in test / calibration data and performance specification on account of malfunctioning of the standard / instrument /equipment due to any damage caused to it after the report, in respect of it has been issued.
- 2. The report shall not be regarded in any way diminishing the normal contractual responsibilities / obligations between the customer and ERTL (W).
- 3. The result reported in this report are valid only at the time of and under the stated conditions of the measurements.

ELECTRONICS REGIONAL TEST LABORATORY (WEST)	REPORT NO.
MINISTRY OF I.T. AND COMMUNICATIONS (STQC DTE)	ERTL(W)/2002 EMI 150
SUBJECT: EMC TESTING OF DIGITAL MULTIMETER 9A 02	DATE PAGE OF 3 MAR 2003 1 4

#### **SCOPE** 1.

1.1 Service Request No :ERTL(W)/2002 0994

1.1.1 Service Request finalised on

: 23 MAY 2002

1.2 Requested by

(Name and address of organisation)

:MECO INSTRUMENTS PVT. LTD, 301, BHARAT INDUSTRIAL ESTATE,

T.T. ROAD, SEWREE MUMBAI 400 015

1.3	<u>Item No.</u>	<u>Description</u>	<u>Qty</u>	Manufacturer and Type No.	Serial No.
	1.	DIGITAL MULTIMETER 9A 02	01	MECO INSTRUMENTS 9A 02	
1.4	Test specific	cations	BS	S EN 61326 (Edition 1998)	

1.5

Temperature :

(25 <u>+</u>2) deg.C (55 <u>+</u>5) % RH

Humidity

1.6 Test Equipment used :

Lab Ambient

1. EMI/003 : ESD Simulator (Schaffner, NSG 432) 2. EMI/034 : RS Chamber (Keytek, G-Strip)

3. EMI/036 : RF Signal Generator (HP, 8648 A)

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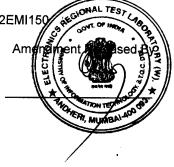
## 2.0 Test Results

Sr.	Test	Test Condition	Requirement	Observation	Remarks
No	/Parameter				
2.1	Electrostatic Discharge	AS per BSEN 61326,1998 Table A.1 EUT in normal operating condition as per Annexure 'A' Test Setup: As per IEC 61000-4-2 Mode of simulation: Air Discharge Test Voltage: Air Discharge: 8kV No. of Discharges: 10 Polarity: ±ve Air Discharge points: Front panel Display And switches	The EUT shall continue to perform satisfactorily after the test as per Annexure 'A'.  Performance Criterion: 'B' (During testing, temporary degradation, or loss of function or performance which is self recoverable)	The EUT was found to perform satisfactorily during and after the test and all parameters were within limits as per Annexure 'A'.	Complies with Criterion 'A' (During testing Normal performance within specification limits)
2.2	Radiated Susceptibility	AS per BSEN 61326,1998, Table A.1  EUT in normal operating condition as per Annexure 'A'  Test Setup: As per IEC 61000-4-3 Frequency Range: 80 MHz to 1000MHz Modulation: 80 % AM @ 1 kHz Field Strength: 10 V/m. Simulation: Using Gstrip <sup>TM</sup> RF Immunity Test Chamber	The EUT shall continue to perform satisfactorily during and after the test as per Annexure 'A'.  Performance Criterion: 'A' (During testing Normal performance within specification limits)	The EUT was found to perform satisfactorily during and after the test and all parameters were within limits as per Annexure 'A'.	Complies with Criterion 'A'

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EUT : Equipmnet Under Test

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3.0 General Remarks: Nil

REPORT APPROVED BY	REPORT RELEASED BY	
HEAD (EMI/PCT)	OIC (CSC)	

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#### ANNEXURE 'A'

### **Functional Check**

Allowable variation in reading shall be within:

- 1. DC Voltage:  $\pm$  (0.5 % of the reading + 4 digits) on 340mV/3.4 V
- 2.  $\pm$  (0.7 % of the reading + 4 digits) on 34V/340 V
- 3.  $\pm$  (1.0 % of the reading + 4 digits) on 1000V
- 4. AC Voltage:  $\pm$  (1.0 % of the reading + 8 digits) on all ranges except
- 5.  $\pm$  (1.5 % of the reading + 8 digits) on 750 V
- 6. DC Current:  $\pm$  (1.5 % of the reading + 4 digits)
- 7. AC Current:  $\pm$  (2.2 % of the reading + 4 digits)
- 8. Resistance:  $\pm$  (0.7% of the reading + 4 digits) on all ranges except
- 9.  $\pm$  (1.2 % of the reading + 4 digits) on 3.4 MOHMS
- 10.  $\pm$  (2.5 % of the reading + 4 digits) on 34 MOHMS
- 11. Frequency:  $\pm$  (1.0 % of the reading +7 digits)

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## **OUR ACCREDITATION STATUS**

ERTL (W) set up under the STQC Directorate, Ministry of Communications & Information Technology, Govt. of India has been accreditated under number of national / international systems as follows:

SYSTEM	AREA	STATUS
IECQ (International Electro-technical Commission on Quality Assessment System for Electronic Components)	Component Testing  ■ Resistors (Fixed)  ■ Capacitors (Fixed)	Accreditated as ITL (Independent Test Laboratory)
NABL (C), India National Accreditational Board for Test & Calibration laboratories (Calibration System)	Calibration  Electro-technical discipline  Thermal discipline  Mechanical discipline	Accreditated Calibration Laboratory
NABL(T), India National Accreditational Board for Test & Calibration laboratories (Testing System)	Electronic & Electrical Testing	Accreditated Test Laboratory
IECEE-CE-Scheme	Mains Operated Electronic Consumer Products	Approved as a CB test Laboratory
Other recognisation		Recognised by CSPO of State Govt., DOT, Naval Docyard, LCSO etc.